Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/686,117	SUGAYA ET AL.	
	Examiner	Art Unit	
	Jinhee J. Lee	2831	

ISSUE CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
174	117F	174	100	72A				
INTERNATIONAL CLASSIFICATION		439	404					
H 0 2 G	1/00							
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Jinhee Lee
(Assistant Examiner) (Date)

Hawkins 6/28/05
(Legal Instruments Examiner) (Date)

Dean A. Reichard
DEAN A. REICHARD
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 2800
(Primary Examiner) (Date) 6/24/05

Total Claims Allowed: 15

O.G. Print Claim(s)	O.G. Print Fig
1	6

☐ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐ R.1.47

Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
1	1		31		61		91		121		151		181
2	2		32		62		92		122		152		182
3	3		33		63		93		123		153		183
7	4		34		64		94		124		154		184
8	5		35		65		95		125		155		185
9	6		36		66		96		126		156		186
10	7		37		67		97		127		157		187
4	8		38		68		98		128		158		188
5	9		39		69		99		129		159		189
	10		40		70		100		130		160		190
	11		41		71		101		131		161		191
6	12		42		72		102		132		162		192
11	13		43		73		103		133		163		193
12	14		44		74		104		134		164		194
13	15		45		75		105		135		165		195
14	16		46		76		106		136		166		196
15	17		47		77		107		137		167		197
	18		48		78		108		138		168		198
	19		49		79		109		139		169		199
	20		50		80		110		140		170		200
	21		51		81		111		141		171		201
	22		52		82		112		142		172		202
	23		53		83		113		143		173		203
	24		54		84		114		144		174		204
	25		55		85		115		145		175		205
	26		56		86		116		146		176		206
	27		57		87		117		147		177		207
	28		58		88		118		148		178		208
	29		59		89		119		149		179		209
	30		60		90		120		150		180		210